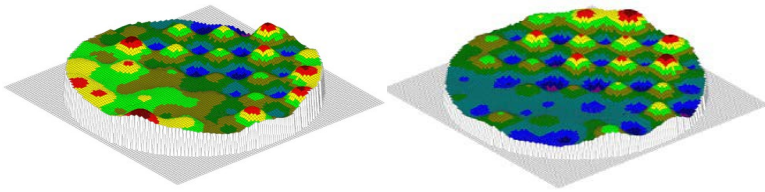


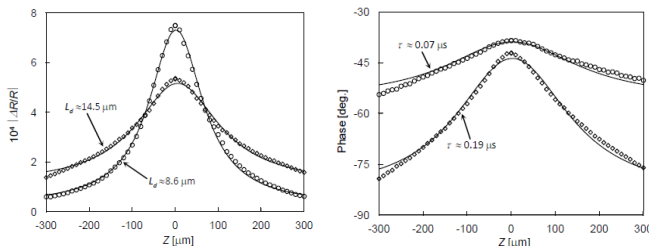
Carrier Metrology System



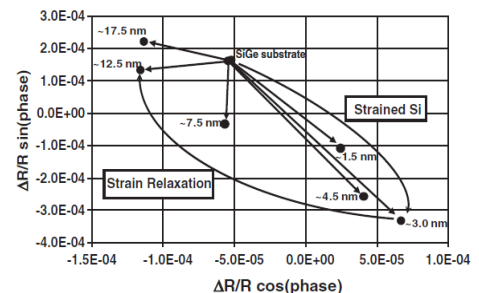
- Carrier Concentration:



- Carrier Mobility & Lifetime:



- Material composition/strain:



For more information visit www.xcalipr.com



Specifications

Features/Model	SiE1	SiGe	SiC
Metrology Module	Z-scanning photoreflectance system with laser probe probe λ : 375 nm probe λ : 450 nm probe λ : 830 nm pump λ : 532 nm pump λ : 532 nm pump λ : 375 nm modulation frequency: 100kHz to 1MHz spatial resolution (carrier conc.): 2 μ m measurement resolution (carrier conc. $\geq 10^{18}/\text{cc}$): 1-2% acquisition time (carrier conc.): 3 seconds measurement resolution (mobility & lifetime): $\leq 1.2\%$ acquisition time (mobility & lifetime): ~30 seconds		
Fab Platform	300mm fully automated metrology tool Dual FOUP configuration OEM robotics 55WPH throughput Remote recipe mgmt & data acquisition		
Analysis Software	Python-based code for mobility & lifetime fitting PC-based offline analysis of Z-scan data Custom fitting protocols for executable on-tool recipes		

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